

Article

# Hot-Pressed Two-Dimensional Amorphous Metals and Their Electronic Properties

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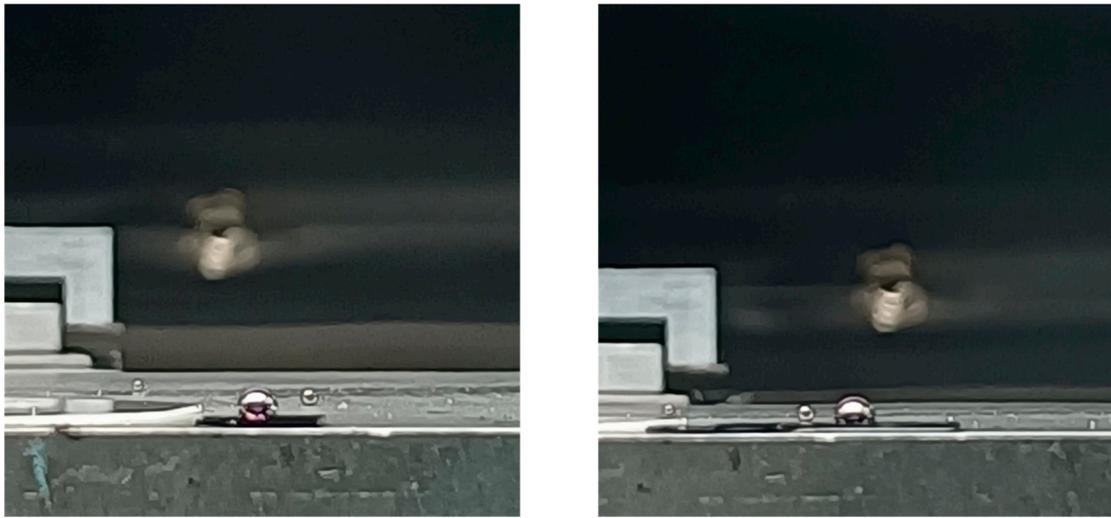
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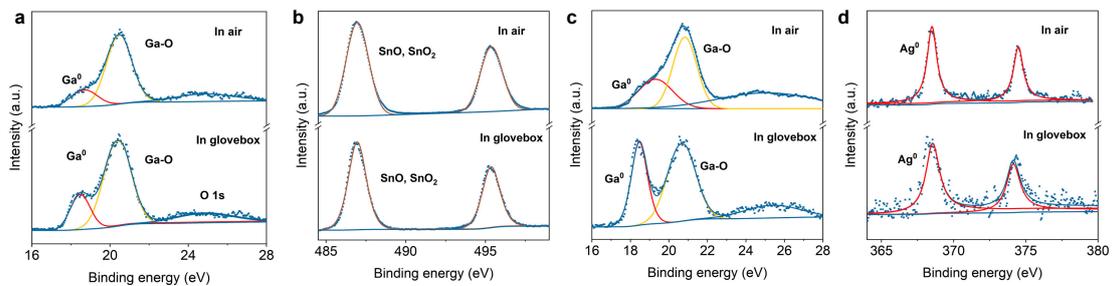


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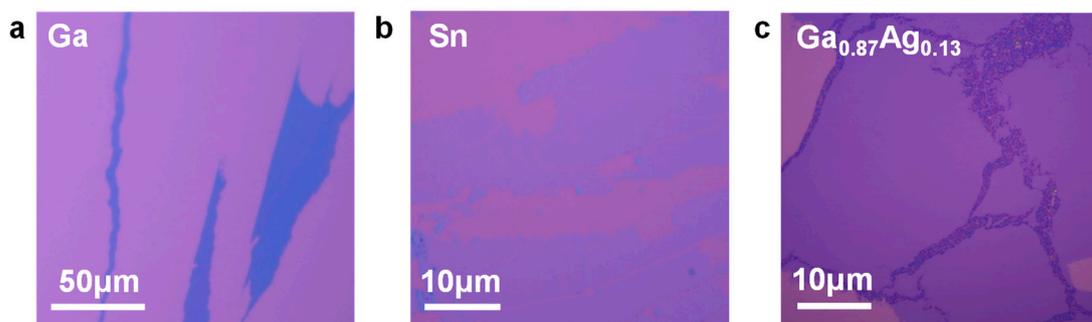
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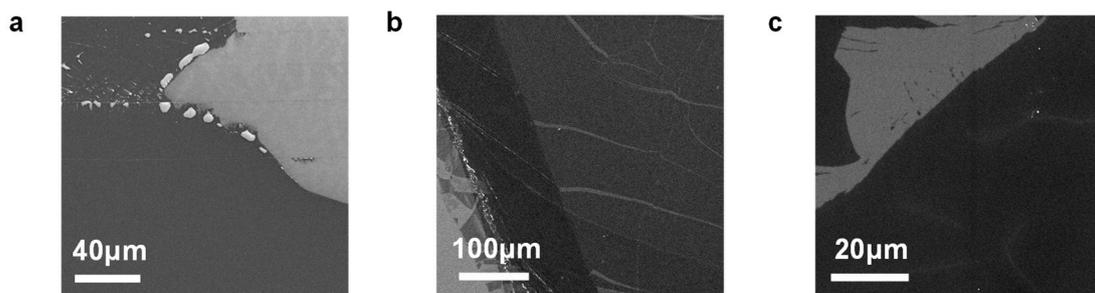
**Figure S1.** The contact angle between liquid bismuth drops and SiO<sub>2</sub>(300nm)/Si substrate without (left) and with (right) O<sub>2</sub> plasma treatment.



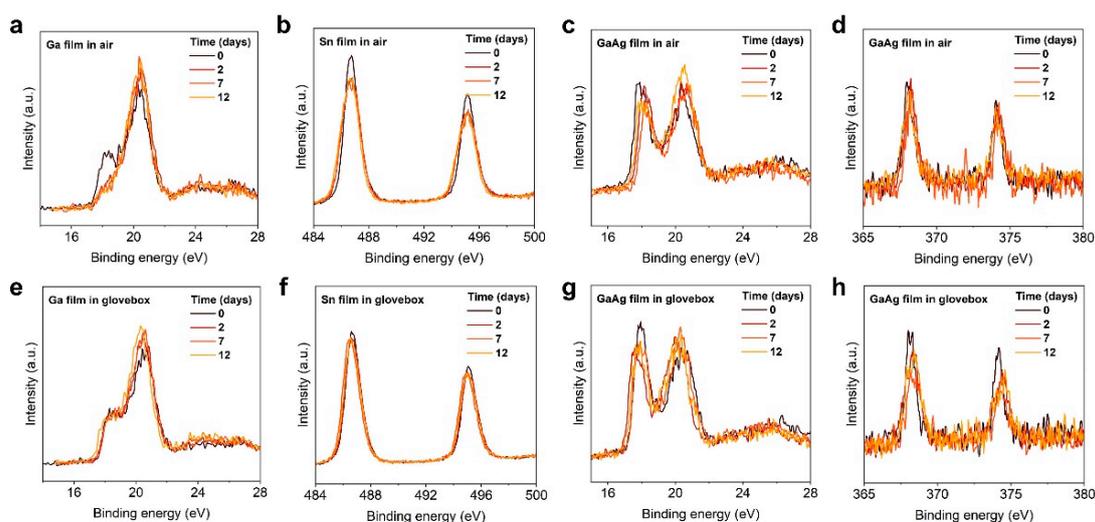
**Figure S2.** XPS spectra of (a) Ga 3d from Ga films, (b) Sn 3d from Sn films, (c) Ga 3d and (d) Ag 3d from Ga<sub>0.87</sub>Ag<sub>0.13</sub> alloy films made in air (top panel) and in glovebox (bottom panel).



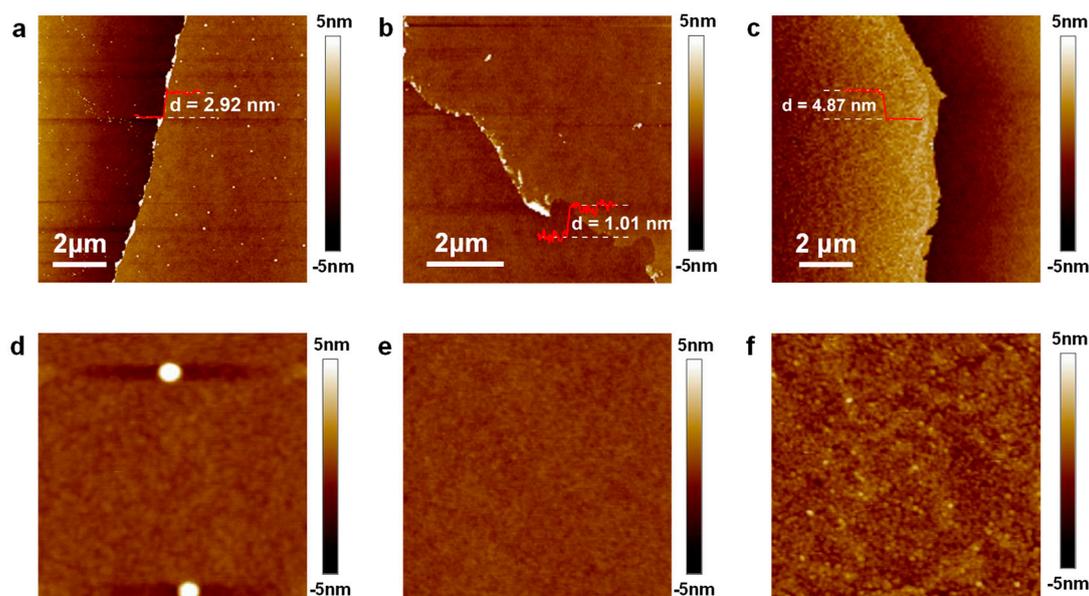
**Figure S3.** Optical images of 2D films made of Ga, Sn, and Ga<sub>0.87</sub>Ag<sub>0.13</sub> alloy in glovebox.



**Figure S4.** SEM images of 2D films made of Ga, Sn, and Ga<sub>0.87</sub>Ag<sub>0.13</sub> alloy synthesized in glovebox.

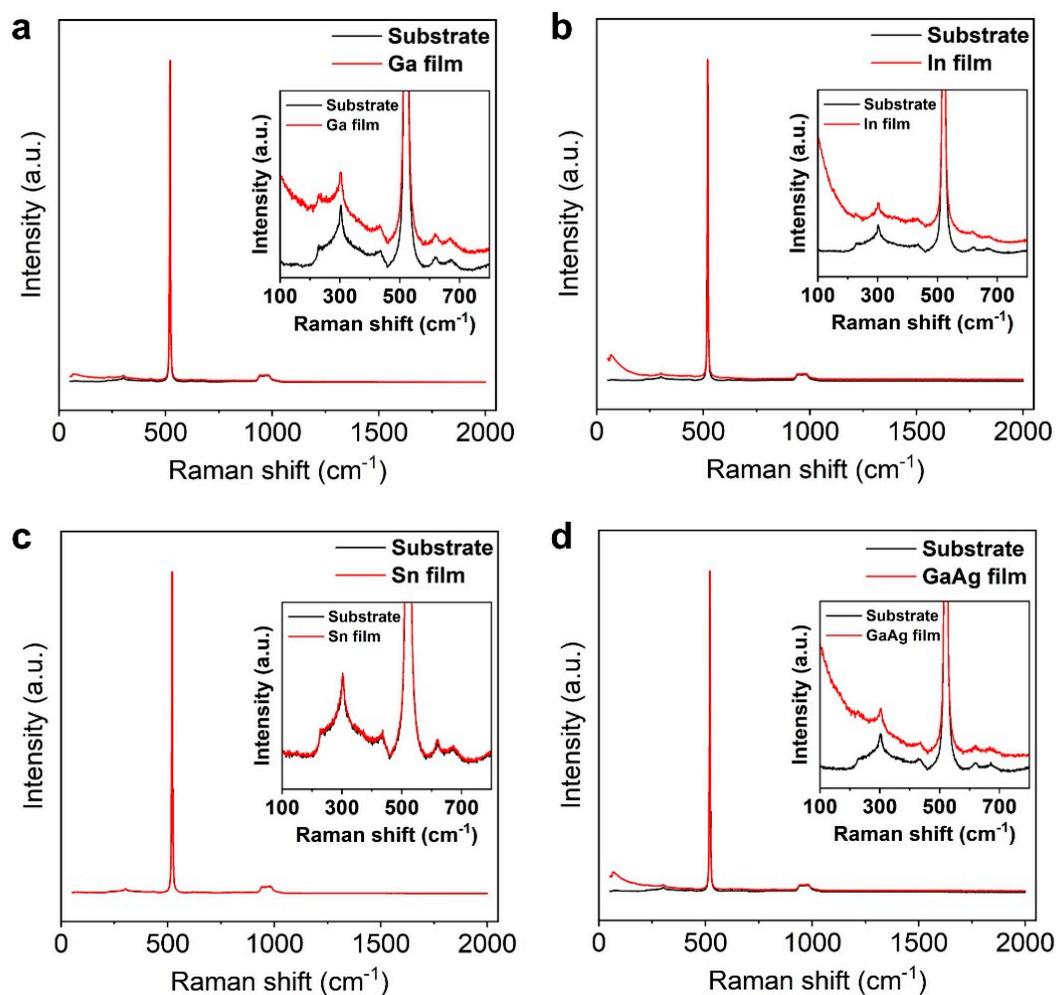


**Figure S5.** The variation of XPS spectrum of films made in glovebox and then stored in air and in glovebox for 12 days. (a, e) XPS of Ga 3d from Ga films stored in air (a) and in glovebox (e); (b, f) XPS of In 3d from In films stored in air (b) and in glovebox (f); (c, g) XPS of Ga 3d from  $\text{Ga}_{0.87}\text{Ag}_{0.13}$  films stored in air (c) and in glovebox (g); (d, h) XPS of Ag 3d from  $\text{Ga}_{0.87}\text{Ag}_{0.13}$  films stored in air (d) and in glovebox (h).

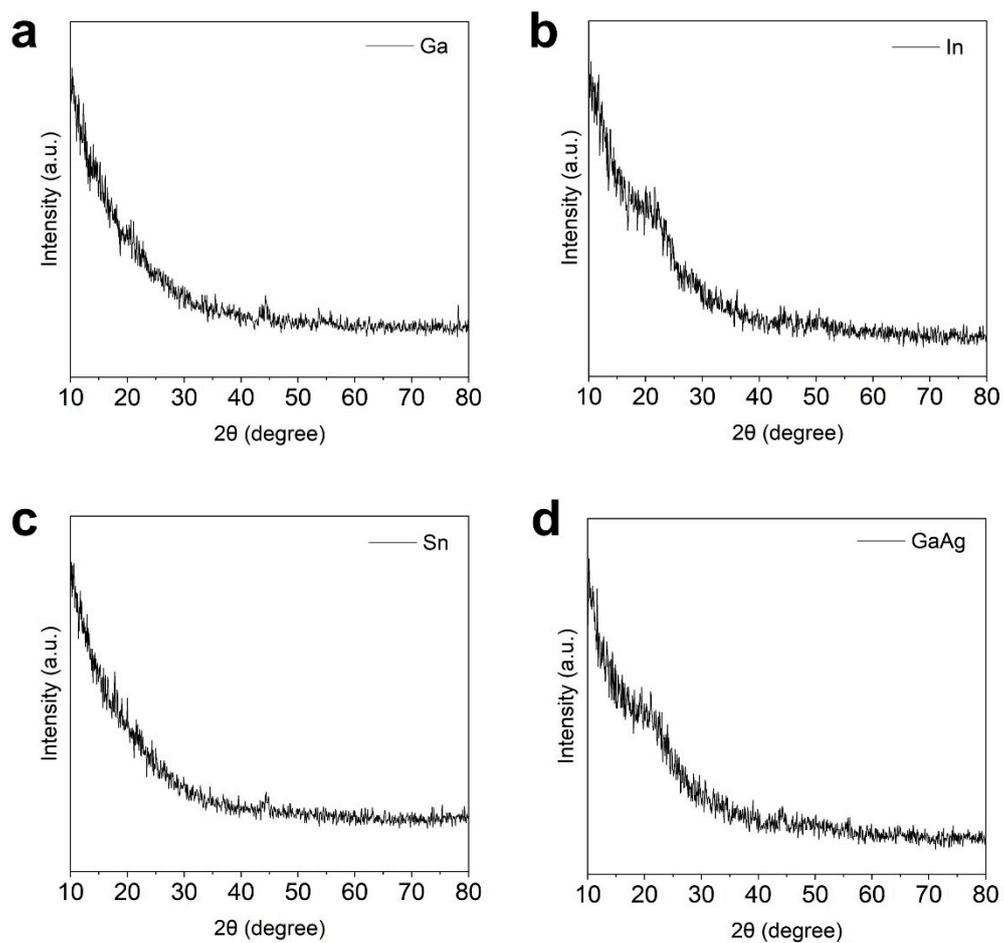


**Figure S6.** AFM images of 2D films made of (a, d) Ga, (b, e) Sn, and (c, f)  $\text{Ga}_{0.87}\text{Ag}_{0.13}$  alloy. (a-c) show the thickness of films. (d-f) show the roughness of films, image width is 1  $\mu\text{m}$ .

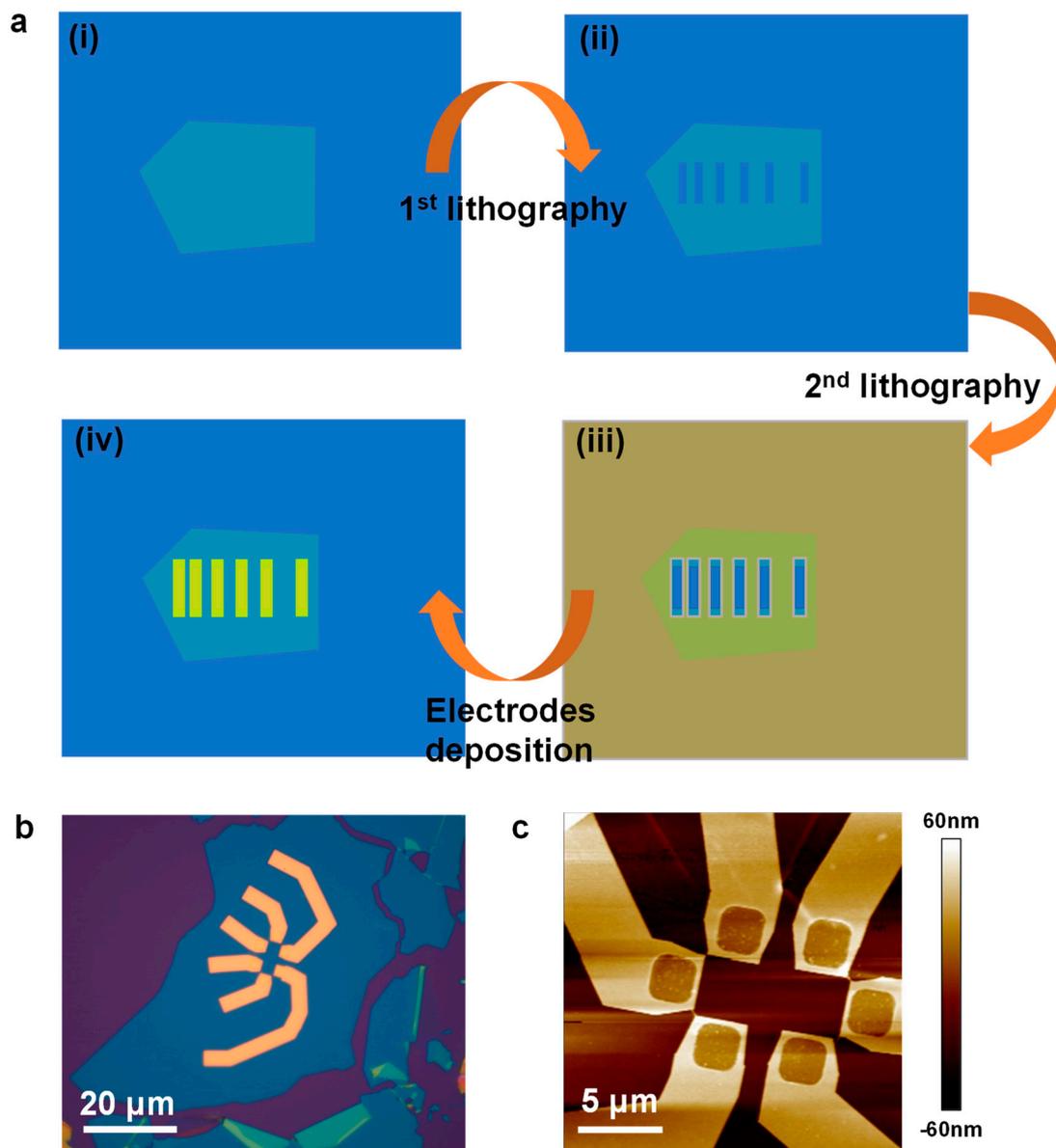
The Raman spectrum of hot-pressed metal films are presented below. As for Ga films and  $\text{Ga}_{0.87}\text{Ag}_{0.13}$  films, according to previous studies [1, 2], solid crystalline gallium and  $\beta\text{-Ga}_2\text{O}_3$  have characteristic Raman peaks at 246  $\text{cm}^{-1}$  and 416  $\text{cm}^{-1}$ . The Raman spectrum of our Ga film (Figure S7a) and  $\text{Ga}_{0.87}\text{Ag}_{0.13}$  film (Figure S7d) show no additional peaks compared to the Raman spectrum of substrate, indicating the absence of either crystalline metal gallium or crystalline  $\text{Ga}_2\text{O}_3$ . As for In films, previous study [3] demonstrates both rhombohedral and body-centered cubic  $\text{In}_2\text{O}_3$  have multiple Raman active modes. The Raman spectrum of our In film (Figure S7b) shows no additional peaks compared to the Raman spectrum of substrate, indicating the absence of crystalline  $\text{In}_2\text{O}_3$ . As for Sn films, both crystal  $\text{SnO}_2$  [4] and  $\text{SnO}$  [5] have characteristic Raman peaks. The Raman spectrum of our Sn film shows no additional peaks compared to the Raman spectrum of substrate, indicating the absence of any crystalline  $\text{SnO}$  and  $\text{SnO}_2$ .



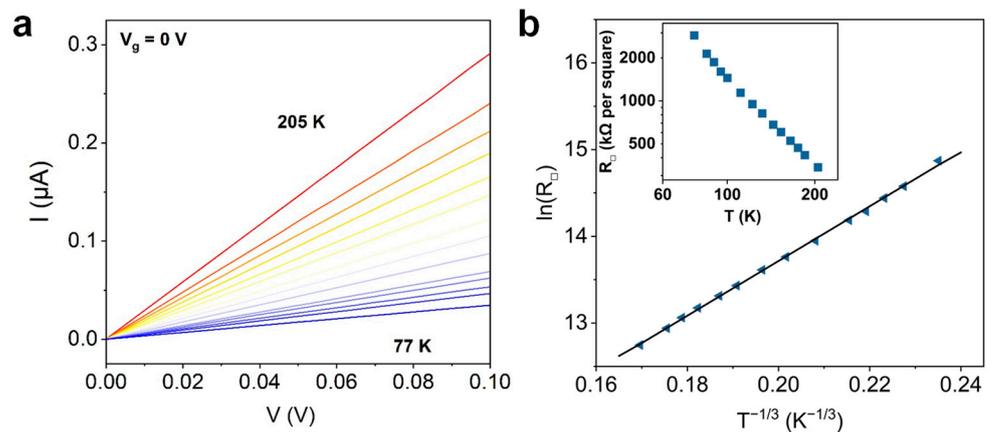
**Figure S7.** Raman spectrum of 2D films made of (a) Ga, (b) In, (c) Sn and (d) Ga<sub>0.87</sub>Ag<sub>0.13</sub> alloy. Insets show the details of the Raman spectrum.



**Figure S8.** XRD spectra of (a) Ga film, (b) In film, (c) Sn film, (d) Ga<sub>0.87</sub>Ag<sub>0.13</sub> alloy film.



**Figure S9.** Fabrication process of h-BN-encapsulated electrodes. (a) Schematic of fabrication procedure of h-BN-encapsulated electrodes: (i) exfoliating h-BN on SiO<sub>2</sub> (300nm)/Si substrate, (ii) first pattern of contact voids on h-BN by EBL lithography and RIE etching, (iii) second lithography of gold electrodes, (iv) electron-beam evaporation of gold electrode. (b) Optical image of h-BN-encapsulated electrodes. (c) AFM image of h-BN-encapsulated electrodes.



**Figure S10.** Electronic properties of Ga film. (a) I versus V curves as a function of temperature showing ohmic contact. (b) The sheet resistance  $R_{\square}$  versus T fitted by 2D Mott's VRH model, inset is double-logarithmic plot of  $R_{\square}$  versus T.

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